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| Notice of References Cited | Application/Control No. 09/605,361 | Applicant(s)/Patent Under Reexamination JASON ET AL. | |
| | Examiner Minh Dieu Nguyen | Art Unit 2132 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-5,854,841 | 12-1998 | Nakata et al. | 713/152 |
| | B | US-6,519,636 | 02-2003 | Engel et al. | 709/223 |
| | C | US-6,253,321 | 06-2001 | Nikander et al. | 713/160 |
| | D | US-6,347,376 | 02-2002 | Attwood et al. | 713/201 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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